



FORM PTO-1449	SERIAL NO. 10/712,418	CASE NO. 10808/109
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE November 12, 2003	GROUP ART UNIT Unknown 2857
(use several sheets if necessary)		APPLICANT(S): E. Steinkirchner et al.

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
m/b	A1	5,586,041	12/17/1996	Mangrulkar	700/124	
m/b	A2	5,726,920	03/10/1998	Chen et al.	702/108	
m/b	A3	2002/0055194 A1	05/09/2002	Takanabe	438/4	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
m/b	A4	GB 2 283 116 A	04/26/1995	United Kingdom		

EXAMINER INITIAL	OTHER ART - NON PATENT LITERATURE DOCUMENTS <small>(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.)</small>	
m/b	A5	Copy of European Search Report dated March 10, 2004 for European Patent Application No. 03026035
m/b	A6	C. Schneider et al., "Automated Photolithography Critical Dimension Controls In A Complex, Mixed Technology, Manufacturing Fab", IBM Microelectronics, 2001 IEEE/SEMI Advanced Semiconductor Manufacturing Conference

EXAMINER <i>Michael Z. Butler</i>	DATE CONSIDERED 12/16/04
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.